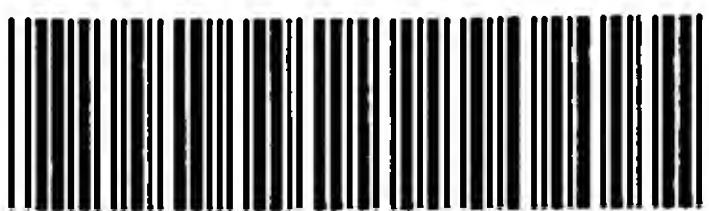


Search Notes**Application/Control No.**

10/708,829

Examiner

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Applicant(s)/Patent under Reexamination

BEENAU ET AL.

Art Unit

2635

SEARCHED

Class	Subclass	Date	Examiner
340	5.53	5/19/2006	NN
340	5.2	5/19/2006	NN
340	5.4+	5/19/2006	NN
340	5.52	5/19/2006	NN
340	5.6	5/19/2006	NN
340	5.8+	5/19/2006	NN
340	10.1	5/19/2006	NN
340	10.4-10.5	5/19/2006	NN
235	379	5/19/2006	NN
235	380	5/19/2006	NN
235	492	5/19/2006	NN
705	35,54,76	5/19/2006	NN
705	186,194	12/10/2005	NN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search East: USPAT; US-PUB; EPO;JPO and Derwent. (UPDATED SEARCH)	5/19/2006	NN